

Optimization of J_c of MgB_2/Fe sheath wires by varying SiC addition level and sintering temperature

O. Shcherbakova, R. H. T. Wilke, A. V. Pan, S. X. Dou

*Institute for Superconducting and Electronic Materials, University of Wollongong,
NSW 2522, Australia.*

Pure and nano-SiC added MgB_2/Fe wires were prepared by *in-situ* powder-in-tube method. The nano-SiC addition level varied from 0 to 15 wt%. Samples were sintered at temperatures from 600°C to 1000°C for 30 min. The important finding of this study is that the enhancement in $J_c(H)$ by nano SiC addition can be achieved at different field regions by appropriate compromising of the doping level and sintering temperature.

1. Introduction

The critical current density (J_c) in MgB_2 has been a central topic for extensive research efforts since superconductivity in this compound was discovered [1]. A number of techniques and chemical additives have been used to improve the J_c performance in magnetic fields. The authors' group found that doping of MgB_2 with nano-particle SiC can significantly enhance J_c in high fields with only slight reductions in T_c up to a doping level as high as 30% of B [2]. In the high field region, the J_c for the 10wt% SiC doped sample increased by more than an order of magnitude at all temperatures compared to the undoped sample, that was verified by a number of groups over the past few years [2-9]. However, SiC doping have some negative effect on J_c in the low field region. The J_c for SiC doped MgB_2 was lower than that for undoped MgB_2 below 4 T at 5 K and below 2.5 T at 20 K [3-5]. There are many applications in the low field region, such as open MRI, transformers and electric cables which normally operate at around 1 T to 3 T. Thus, it is important that the enhancement of J_c by SiC doping can be extended to include all the field regions. In this work we will show that the improvement of J_c in SiC added MgB_2 can be achieved in all fields regions by varying SiC addition level and sintering profile.

2. Sample preparation

Fe-sheath MgB_2 wires were prepared in-situ using the standard powder-in-tube technique [3, 6]. Powders of magnesium (99%) and amorphous boron (99%) were well mixed for fabrication of pure MgB_2 wire. SiC added MgB_2 wires were prepared from powders with atomic ratios Mg:2B plus 5 wt%, 10 wt% or 15 wt% of SiC additions. The detailed description of wire preparation can be found elsewhere [10].

Table 1. The list of studied pure and SiC added MgB_2 samples.

#	SiC addition level, %	Sintering profile	#	SiC addition level, %	Sintering profile
1	0	650°C×30 min	7	10	650°C×30 min
2	0	825°C×30 min	8	10	825°C×30 min
3	0	1000°C×30 min	9	10	1000°C×30 min
4	5	650°C×30 min	10	15	650°C×30 min
5	5	825°C×30 min	11	15	825°C×30 min
6	5	1000°C×30 min	12	15	1000°C×30 min

The composite wires were sintered in a tube furnace at 650⁰C, 825⁰C, and 1000⁰C for 30 min and finally furnace-cooled to room temperature. A high purity argon gas flow was maintained throughout the sintering process. The description of studied samples is presented in Table 1.

3. Results

3.1 Critical Temperature

The critical temperature values, T_c , were measured by SQUID magnetometer. The T_c values of undoped and SiC doped MgB₂/Fe wires sintered at different temperatures are presented on Fig. 1a. For each sintering temperature in studied samples, the increasing of SiC addition level resulted in more significant T_c suppression due to the reaction between SiC and MgB₂. On the other hand, for both pure and SiC-added wires, the T_c increased with increasing sintering temperature. The increase of T_c can be explained by the improvement of the crystallinity of the MgB₂ core with increasing sintering temperature [11].

3.2 Magnetic Characterization

Fig. 1b shows magnetic J_c vs H curves at 20 K for the undoped and SiC added MgB₂ wires sintered at 825⁰C for 30 minutes. As can be seen, in self-field and 20 K J_c for 5 wt% SiC added MgB₂ wire reached the same value of 400,000 A/cm² as pure MgB₂ wire. At low fields the J_c values for the 10 wt% and 15 wt% SiC added wires were lower than those of the undoped sample. All SiC added samples showed more than one order of magnitude increase in J_c values at higher field regions. The $J_c(H)$ behavior for all these samples sintered at 650⁰C (see insert in Fig.1b) showed the same trend as that for samples sintered at 825⁰C, but the J_c values in self field were lower than those obtained for the samples sintered at 825⁰C. It is evident that for low field applications 5 wt% SiC doping gives the best performance in $J_c(H)$, without any degradation even in self-field.

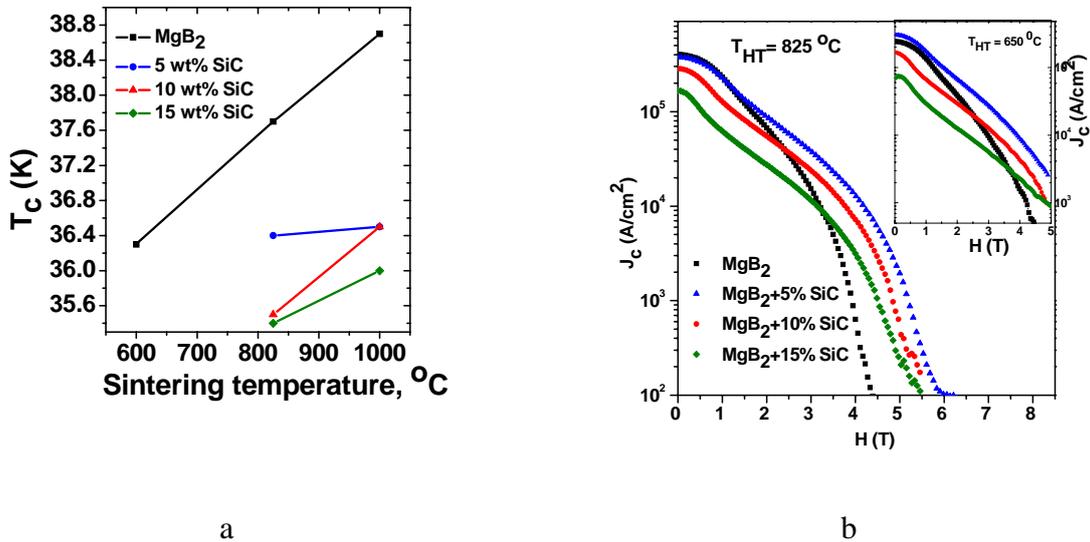


Figure 1. a) Critical temperature of studied samples vs sintering temperature; b) critical current density of pure and SiC added MgB₂ samples sintered at 825⁰C and 650⁰C (insert).

Fig 2a,b presents transport $J_c(H)$ measured at 4.2 K in the field range of 5 T to 15 T for the doped and undoped wires sintered at 650⁰C and 825⁰C. First, there was a clear distinguishable difference in $J_c(H)$ for the undoped and SiC doped wires, the J_c value for the doped wires at all three doping levels being significantly higher than that of undoped one.

Furthermore, there were a cross over of the best $J_c(H)$ from 5 wt% SiC doped wire in the low field range (0 T to 5T) to 10 wt% SiC doped wire in the high field range (8 T to 15 T). Higher doping level results in larger amount of Mg_2Si impurities that act as effective pinning centers improving $J_c(H)$ performance in high field region [10].

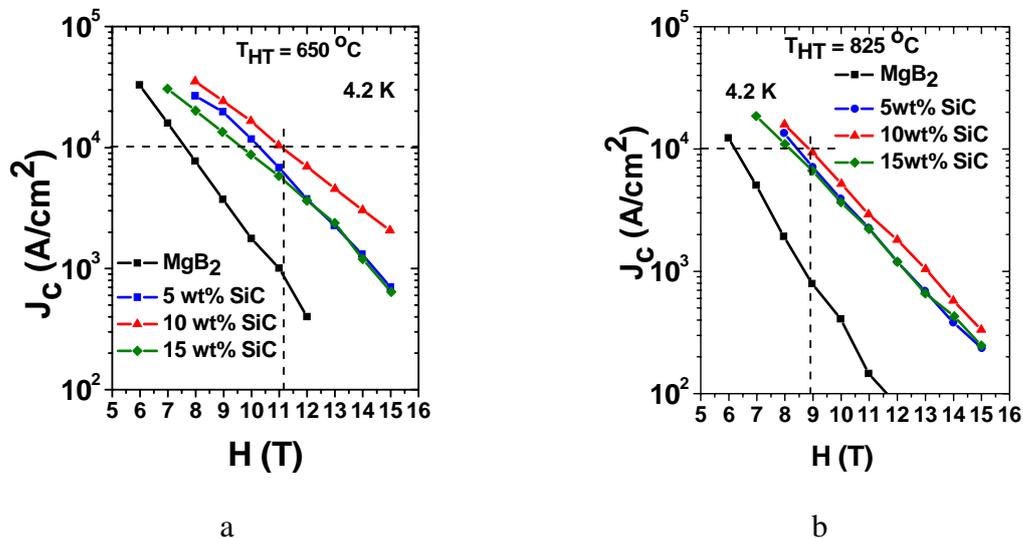


Fig. 2. Transport critical current densities of samples sintered at 650^oC (a) and 825^oC (b).

Another important thing is the effect of sintering profile on J_c value. One can see, that only reducing of sintering temperature from 825^oC to 650^oC allowed increasing working field by 2T. For example, the J_c level of 10⁴ A/cm² was reached at 9T for sample with 10wt% SiC addition sintered at 825^oC (see Fig. 2b) and at 11T for sample sintered at 650^oC (see Fig.2a).

4. Conclusion

We have shown that the $J_c(H)$ in MgB_2 samples can be optimized for different field regions by varying the SiC doping level and sintering temperature. To achieve a high critical current in low fields region, a low doping level of 5wt% SiC and higher sintering temperature (825^oC) should be used. For high field regions of 8-15 T addition level of 10wt % SiC and sintering temperature of 650^oC resulted in the best J_c value.

Acknowledgments

The authors would like to thank Dr. M. Bhatia from Ohio State University, USA for transport measurements, the Australian Research Council and the University of Wollongong for financial support.

References

- [1] J. Nagamatsu et al, *Nature* **410**, 64 (2001)
- [2] S.X. Dou et al, *J. Appl. Phys.* **94**, 1850-1856 (2003).
- [3] S.X. Dou, et al., *Appl. Phys Lett.* **81**, 3419-3421 (2002).
- [4] Y. Ma et al, *Supercond. Sci. Technol.* **16**, 852 (2003).
- [5] A. Yamamoto et al, *Supercond. Sci. Technol.* **18**, 116-121(2005).
- [6] S. Soltanian et al, *Supercond. Sci. Technol.* **18**, 658-666 (2005).
- [7] M. Sumption et al, *Supercond. Sci. Technol.* **17**, 1180 (2004).
- [8] S. Soltanian et al, *IEEE Trans. on Appl. Supercond.* **13**, 3273 (2003).
- [9] A. Serquis et al, *Supercond. Sci. Technol.* **17**, L35-L37 (2004)
- [10] O. Shcherbakova et al, in preparation
- [11] H. Kumakura et al, *Supercond. Sci. Technol.* **18**, 1042-1046 (2005)